
Table of Contents

1.0 SCOPE AND PURPOSE.....	1
1.1 PURPOSE.....	1
1.2 SCOPE.....	1
2.0 SIMPLIFICATION OF NON-SUPPLY TO NON-SUPPLY (I/O TO I/O) TESTING	1
3.0 NON-SUPPLY STRESS TO ASSOCIATED SUPPLY PIN GROUPS.....	2
4.0 EXAMPLE HBM TEST OF A DEVICE WITH CROSS DOMAINS	4
4.1 REDUCTION IN HBM TEST TIME	7
5.0. NEW ALLOWANCE FOR SHORTED NON-SUPPLY PINS	10
6.0 STRESS POLARITIES OF SUPPLY PINS.....	10
7.0 REPORTING	11
8.0 INDUCTIVE CURRENT TRANSDUCER	11
9.0 NO CONNECT PIN CHANGES	11
10.0 CHANGES IN DEVICE CLASSIFICATION	12
11.0 TWO-PIN TESTERS	12
11.1 LOW PARASITIC HBM TESTER VERIFICATION PROCEDURE	17
12.0 CONCLUSIONS	21
13.0 REFERENCES	22

TABLES

Table A1: Example of Association of the Supply Pins to Non-Supply Pins	3
Table A2: Example of HBM Test Plan Example using Table 2A	6
Table A3: Calculation of Number of HBM Pulses using Table 2A.....	8
Table A4: Calculation of Number of HBM Pulses using Table 2B.....	9
Table A5: Comparison of Routine Verification Requirements	14
Table A6: The Differences between Relay-Based and Two-Pin Testers	16
Table A7: Measured Parameters of Short Circuit and 500-Ohm Load Waveforms.....	21

FIGURES

Figure 1:	Illustrates the Ideas of Group, Multiple Power Supplies and Coupled Non-Supply Pin Pairs	5
Figure 2:	Pin out of 8 Pin Example Product.....	7
Figure 3:	Example of Waveform Measurement Setup with Evaluation Load at the DUT Location	15
Figure 4:	Illustrates the Tester Parasitic Affects on the Terminal A and B Discharge HBM Currents	17
Figure 5:	Shorting Test Device for Low Parasitic Tester Evaluation	18
Figure 6:	HBM Tester being Evaluated for Low Parasitics	19
Figure 7:	40 Pin DIP Shorting Test Device with the Current Probe Connected between the Unconnected Pin 1 and Group Connected Pin 40	19
Figure 8:	Applying the Negative Pulse (Terminal A) to Pin 40 with Pin 1 Grounded (Terminal B)	20
Figure 9:	Plot of Waveforms from a Low Parasitic Tester	21
Figure 10:	Plot of 500-Ohm Load Waveforms from a Low Parasitic Tester	21